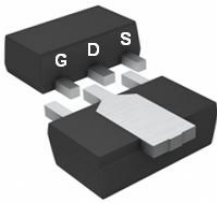


# PF610BC

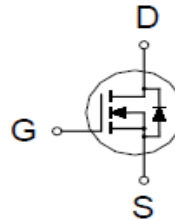
## N-Channel Enhancement Mode MOSFET

### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
100V	$0.7\Omega @ V_{GS} = 10V$	1.1A



**SOT-89**



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ }^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	100	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_A = 25\text{ }^\circ\text{C}$	$I_D$	1.1	A
	$T_A = 70\text{ }^\circ\text{C}$		0.9	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	5	
Avalanche Current		$I_{AS}$	3.8	
Avalanche Energy	$L = 1\text{mH}$	$E_{AS}$	7.2	mJ
Power Dissipation	$T_A = 25\text{ }^\circ\text{C}$	$P_D$	1.9	W
	$T_A = 70\text{ }^\circ\text{C}$		1.2	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	$^\circ\text{C}$

### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		65	$^\circ\text{C} / \text{W}$
Junction-to-Case	$R_{\theta JC}$		12	

<sup>1</sup>Pulse width limited by maximum junction temperature.

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## N-Channel Enhancement Mode MOSFET

### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

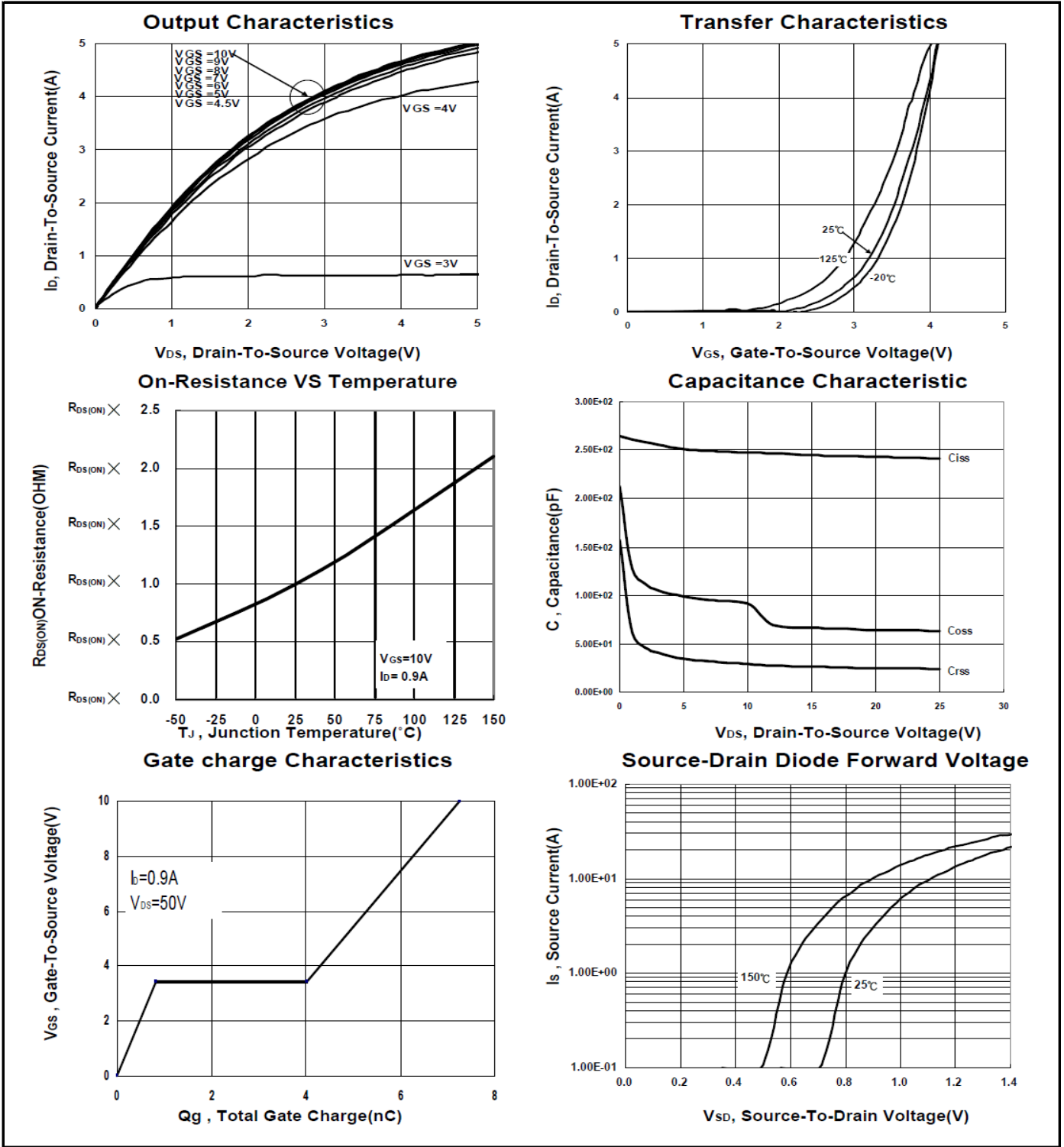
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	100			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1	1.8	3	
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V			±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 70 °C			10	
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.5A		0.6	0.9	Ω
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.9A		0.5	0.7	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 0.9A		1.7		S
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V, f = 1MHz		244		pF
Output Capacitance	C <sub>oss</sub>			63		
Reverse Transfer Capacitance	C <sub>rss</sub>			24		
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V, f = 1MHz		1.5		Ω
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>DS</sub> = 0.5V <sub>(BR)DSS</sub> , V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.9A		7		nC
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>			1		
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>			3		
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>	V <sub>DS</sub> = 50V, I <sub>D</sub> ≅ 0.9A, V <sub>GS</sub> = 10V, R <sub>GEN</sub> = 6Ω		25		nS
Rise Time <sup>2</sup>	t <sub>r</sub>			33		
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>			47		
Fall Time <sup>2</sup>	t <sub>f</sub>			25		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>J</sub> = 25 °C)</b>						
Continuous Current	I <sub>S</sub>				1.1	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = 0.9A, V <sub>GS</sub> = 0V			1.2	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 2A, di/dt = 100A / μS		34		nS
Reverse Recovery Charge	Q <sub>rr</sub>				37	

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

# PF610BC

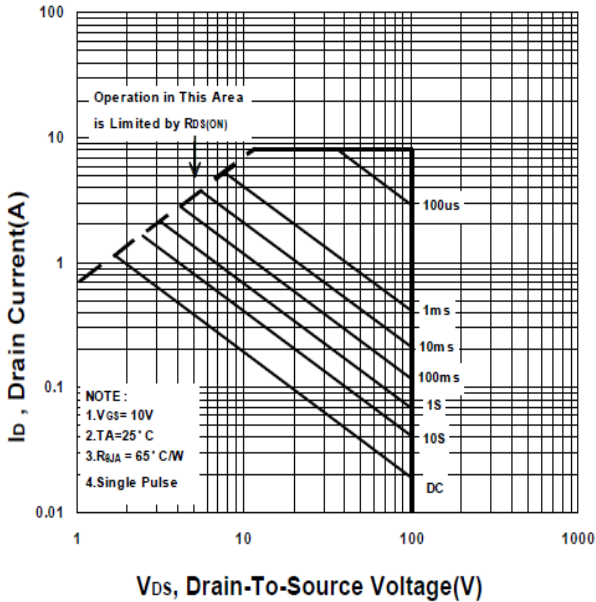
## N-Channel Enhancement Mode MOSFET



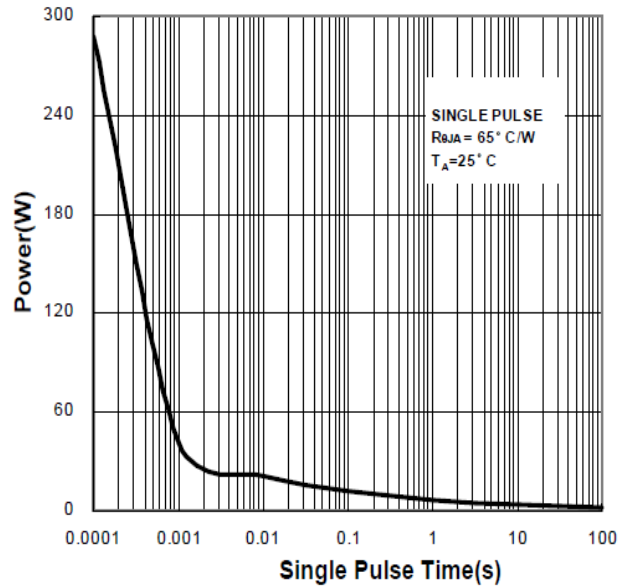
# PF610BC

## N-Channel Enhancement Mode MOSFET

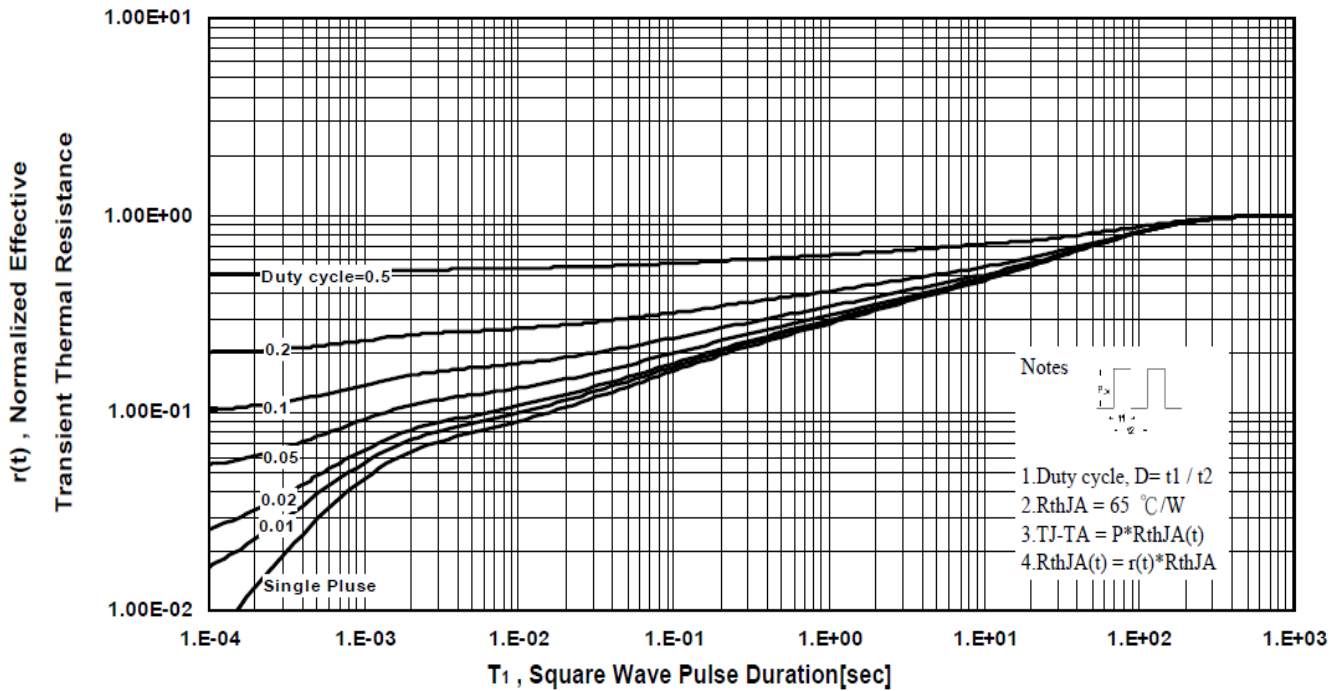
**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**



**PF610BC**  
**N-Channel Enhancement Mode MOSFET**

**SOT-89 MECHANICAL DATA**

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.45	4.5	4.55	G	0.36	0.50	0.56
B	1.4	1.7	1.8	H	1.3	1.5	1.7
C	0	0.7	1.05	I	2.8	3.0	3.2
D	2.3	2.5	2.6	J	1.4	1.5	1.6
E	0.8	1.04	1.2	K	3.8	4.2	4.25
F	0.3	0.46	0.52	L	0.35	0.4	0.44

